

N-Channel 30 V (D-S) MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	$R_{DS(on)}(\Omega)$	I _D (A) ^{a, e}	Q _g (Typ.)		
30	0.0073 at V _{GS} = 10 V	45	53 nC		
30	$0.0102 \text{ at V}_{GS} = 4.5 \text{ V}$	40	33110		

FEATURES

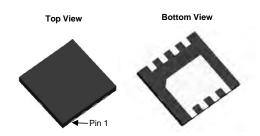
- TrenchFET® Power MOSFET
- 100 % R_g and UIS Tested

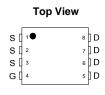


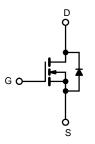
APPLICATIONS

- · Notebook PC Core
- VRM/POL

DFN 3x3 EP







N-Channel MOSFET

Parameter		Symbol	Limit	Unit	
Drain-Source Voltage		V _{DS}	30	V	
Gate-Source Voltage		V_{GS}	± 20		
	T _C = 25 °C		45 ^{a, e}		
Continuous Prain Current (T = 175 °C)	T _C = 70 °C		37 ^e		
Continuous Drain Current (T _J = 175 °C)	T _A = 25 °C	I _D	21 ^{b, c}	A	
	T _A = 70 °C		17.8 ^{b, c}		
Pulsed Drain Current		I _{DM}	135		
Avalanche Current Pulse	L = 0.1 mH	I _{AS}	26		
Single Pulse Avalanche Energy	L=0.11IIII	E _{AS}	53.2	mJ	
Continuous Source-Drain Diode Current	T _C = 25 °C	I _S	45 ^{a, e}	Α	
Continuous Source-Drain Diode Current	T _A = 25 °C	'S	21 ^{b, c}		
	T _C = 25 °C		31.2	W	
Maximum Power Dissipation	T _C = 70 °C	P _D	20		
Maximum Power Dissipation	T _A = 25 °C	' D	3.55 ^{b, c}		
	T _A = 70 °C		2.13 ^{b, c}		
Operating Junction and Storage Temperature R	T _J , T _{stg}	- 55 to 175	°C		

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^{b, d}	t ≤ 10 s	R _{thJA}	31	44	°C/W	
Maximum Junction-to-Case	Steady State	R _{thJC}	3	4	C/VV	

Notes:

- a. Based on T_C = 25 °C. b. Surface mounted on 1" x 1" FR4 board.
- d. Maximum under steady state conditions is 90 °C/W.
- e. Calculated based on maximum junction temperature. Package limitation current is 80 A.



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Parameter	Symbol	Test Conditions	Min .	Тур.	Max.	Unit
Static			•			
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	30			V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I _D = 250 μA		35		mV/°C
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_{J}$	i _D = 250 μA		- 5.5		
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	0.5		1.5	V
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA
Zana Oata Wallana Basin Oamani	1	V _{DS} = 30 V, V _{GS} = 0 V			1	μΑ
Zero Gate Voltage Drain Current	IDSS	V _{DS} = 30 V, V _{GS} = 0 V, T _J = 55 °C			10	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	45			Α
	_	V _{GS} = 10 V, I _D = 12 A		0.0073	0.0081	Ω
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 4.5 \text{ V}, I_D = 9 \text{ A}$		0.0102	0.012	
Forward Transconductance ^a	9 _{fs}	V _{DS} = 15 V, I _D = 12 A	İ	100		S
Dynamic ^b						
Input Capacitance	C _{iss}			1520		pF
Output Capacitance	C _{oss}	$V_{DS} = 12.5 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		1003		
Reverse Transfer Capacitance	C _{rss}			941		
Total Gate Charge	Q _g	$V_{DS} = 15 \text{ V}, V_{GS} = 10 \text{ V}, I_{D} = 12 \text{ A}$		71	 	nC
				61.5		
Gate-Source Charge	Q _{gs}	$V_{DS} = 15 \text{ V}, V_{GS} = 4.5 \text{ V}, I_{D} = 9 \text{ A}$		34		
Gate-Drain Charge	Q _{gd}			29		
Gate Resistance	R _g	f = 1 MHz		1.4	2.1	Ω
Turn-On Delay Time	t _{d(on)}			18	27	
Rise Time	t _r	V_{DD} = 15 V, R_L = 0.555 Ω		11	17	
Turn-Off Delay Time	t _{d(off)}	$I_D\cong 7$ A, V_{GEN} = 10 V, R_g = 1 Ω		70	105	
Fall Time	t _f			10	15	
Turn-On Delay Time	t _{d(on)}			55	83	ns
Rise Time	t _r	V_{DD} = 15 V, R_L = 0.625 Ω		180	270	
Turn-Off Delay Time	t _{d(off)}	$I_D\cong 4$ A, V_{GEN} = 4.5 V, R_g = 1 Ω		55	83	
Fall Time	t _f			12	18	
Drain-Source Body Diode Characteristic						
Continuous Source-Drain Diode Current	Is	T _C = 25 °C			45	
Pulse Diode Forward Current ^a	I _{SM}				135	Α
Body Diode Voltage	V _{SD}	I _S = 12 A		0.8	1.2	V
Body Diode Reverse Recovery Time	t _{rr}		İ	52	78	ns
Body Diode Reverse Recovery Charge	Q _{rr}	1 40 4 31/44 400 4/ 7 07:00		70.2	105	nC
Reverse Recovery Fall Time	t _a	$I_F = 10 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 ^{\circ}\text{C}$		27		
Reverse Recovery Rise Time	t _b			25		ns

Notes:

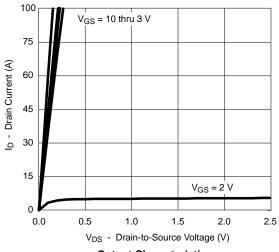
- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

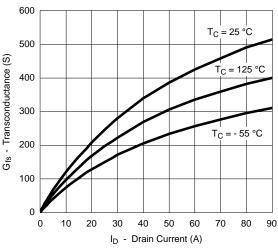




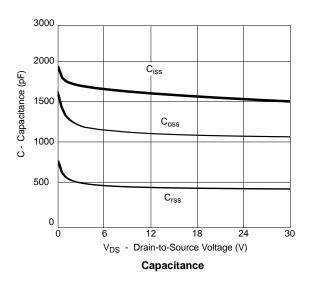
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

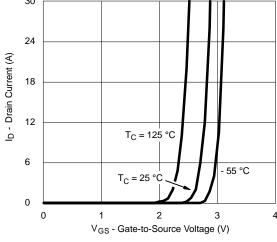


Output Characteristics

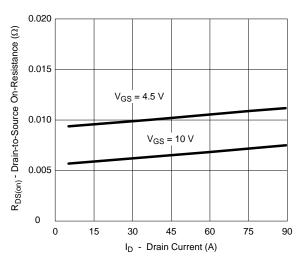


Transconductance

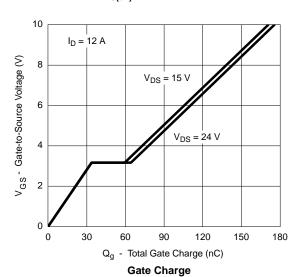




Transfer Characteristics

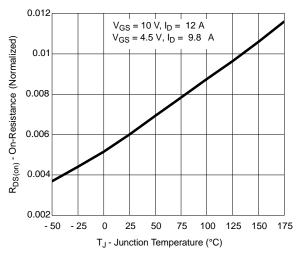


R_{DS(on)} vs. Drain Current

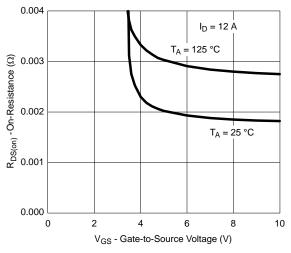




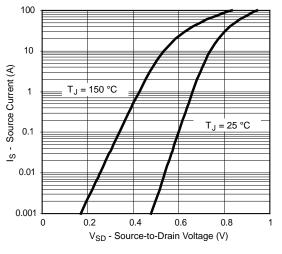
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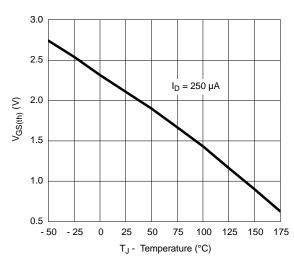
On-Resistance vs. Junction Temperature



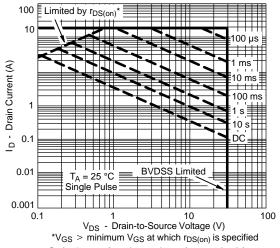
 $R_{DS(on)}$ vs. V_{GS} vs. Temperature



Forward Diode Voltage vs. Temperature



Threshold Voltage

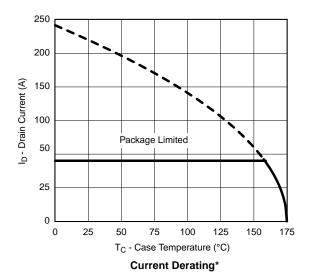


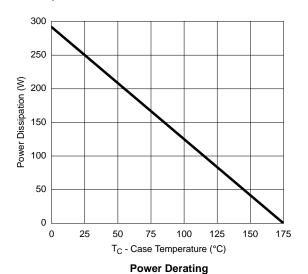
Safe Operating Area, Junction-to-Ambient



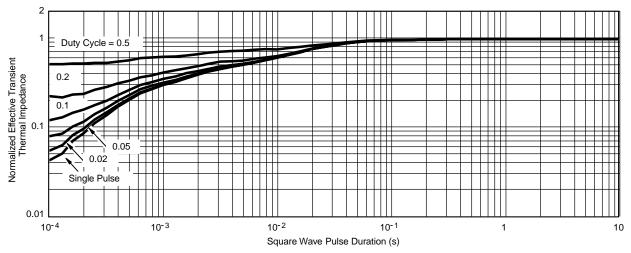


TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

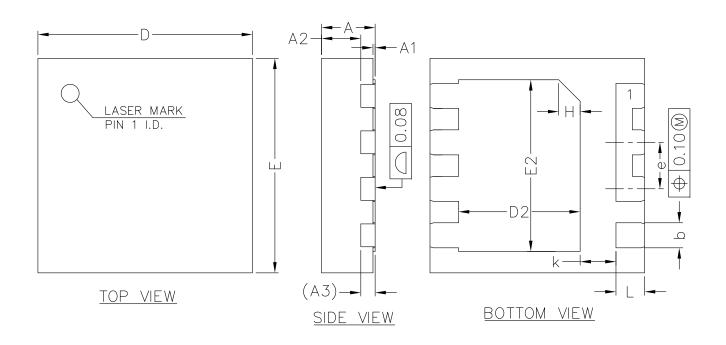


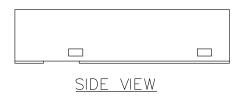


* The power dissipation P_D is based on $T_{J(max)} = 175$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



Normalized Thermal Transient Impedance, Junction-to-Case





COMMON DIMENSIONS (UNITS OF MEASURE=MILLIMETER)

SYMBOL	MIN	NOM	MAX	
Α	0.70	0.75	0.80	
A1	0.00	0.02	0.05	
A2	0.50	0.55	0.60	
А3	0.20REF			
Ь	0.30	0.35	0.40	
D	2.90	3.00	3.10	
Е	2.90	3.00	3.10	
D2	1.60	1.70	1.80	
E2	2.30	2.40	2.50	
е	0.55	0.65	0.75	
K	0.40	0.50	0.60	
L	0.35	0.40	0.45	





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